

Search Notes

Application/Control No.

10/022,730

Examiner

Erin M. File

Applicant(s)/Patent under
Reexamination

JAE SANG CHA

Art Unit

2634

SEARCHED

Class	Subclass	Date	Examiner
375	130	2/23/2005	EMF
375	140	2/23/2005	EMF
375	145	2/23/2005	EMF
375	149	2/23/2005	EMF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM	2/23/2005	EMF
PALM INVENTORSHIP	2/23/2005	EMF